

**Notice of References Cited**

Application/Control No.

10/542,169

Applicant(s)/Patent Under  
Reexamination  
BOYD ET AL.

Examiner

Golam M. M. Shameem, Ph.D.

Art Unit

1626

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*	C	US-7,037,929	05-2006	Pevarello et al.	514/371
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**NON-PATENT DOCUMENTS**

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	U	Pevarello et al (2000): STN International HCAPLUS database, (Columbus, Ohio), Accession number: 2000:314687. ✓
	V	Koo et al (2001): STN International HCAPLUS database, (Columbus, Ohio), Accession number: 2001:780679. ✓
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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